



Truesemi

TSB12N65M/TSI12N65M

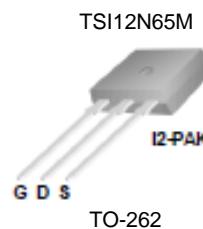
650V N-Channel MOSFET

General Description

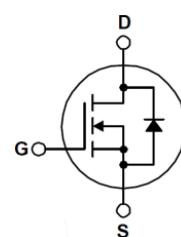
This Power MOSFET is produced using Truesemi's advanced planar stripe DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction based on half bridge topology.



TSB12N65M



TSI12N65M



Features

- 12A,650V,Max. $R_{DS(on)}$ =0.75 Ω @ $V_{GS}=10V$
- Low gate charge(typical 52nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

Absolute Maximum Ratings

$T_J=25^\circ C$ unless otherwise specified

Symbol	Parameter	Value	Units
V_{DSS}	Drain-Source Voltage	650	V
V_{GS}	Gate-Source Voltage	±30	V
I_D	Drain Current $T_C = 25^\circ C$	12	A
		7.4	A
I_{DM}	Pulsed Drain Current (Note 1)	48	A
E_{AS}	Single Pulsed Avalanche Energy (Note 2)	865	mJ
I_{AR}	Avalanche Current (Note 1)	12	A
E_{AR}	Repetitive Avalanche Energy (Note 1)	23	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	4.5	V/ns
P_D	Power Dissipation ($T_C = 25^\circ C$) -Derate above 25°C	230	W
		1.85	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	°C
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	°C

* Drain current limited by maximum junction temperature.

Thermal Resistance Characteristics

Symbol	Parameter	Typ	Max	Units
$R_{\theta JC}$	Thermal Resistance,Junction-to-Case	--	0.54	°C/W
$R_{\theta CS}$	Thermal Resistance,Case-to-Sink Typ.	--	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance,Junction-to-Ambient	--	62.5	°C/W

Electrical Characteristics $T_J=25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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On Characteristics

V_{GS}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2.0	--	4.0	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}$, $I_D = 6 \text{ A}$	--	0.63	0.75	Ω
g_{FS}	Forward transconductance	$V_{GS}=40\text{V}, I_D=6\text{A}$ (Note 4)	--	13	--	S

Off Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$	650	--	--	V
$\Delta BVDSS / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C	--	0.6	--	$\text{V}/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}$, $V_{GS} = 0 \text{ V}$	--	--	1	μA
		$V_{DS} = 520 \text{ V}$, $T_J = 125^\circ\text{C}$	--	--	10	μA
I_{GSSF}	Gate-Body Leakage Current,Forward	$V_{GS} = 30 \text{ V}$, $V_{DS} = 0 \text{ V}$	--	--	100	nA
I_{GSSR}	Gate-Body Leakage Current,Reverse	$V_{GS} = -30 \text{ V}$, $V_{DS} = 0 \text{ V}$	--	--	-100	nA

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$	--	1850	--	pF
C_{oss}	Output Capacitance		--	180	--	pF
C_{rss}	Reverse Transfer Capacitance		--	20	--	pF

Switching Characteristics

$t_{d(on)}$	Turn-On Time	$V_{DS} = 325 \text{ V}$, $I_D = 12 \text{ A}$, $R_G = 25 \Omega$ (Note 4,5)	--	30	--	ns
t_r	Turn-On Rise Time		--	90	--	ns
$t_{d(off)}$	Turn-Off Delay Time		--	140	--	ns
t_f	Turn-Off Fall Time		--	90	--	ns
Q_g	Total Gate Charge	$V_{DS} = 520 \text{ V}$, $I_D = 12 \text{ A}$, $V_{GS} = 10 \text{ V}$ (Note 4,5)	--	52	--	nC
Q_{gs}	Gate-Source Charge		--	8.5	--	nC
Q_{gd}	Gate-Drain Charge		--	20	--	nC

Source-Drain Diode Maximum Ratings and Characteristics

I_S	Continuous Source-Drain Diode Forward Current	--	--	12	A	
I_{SM}	Pulsed Source-Drain Diode Forward Current	--	--	48		
V_{SD}	Source-Drain Diode Forward Voltage	$I_S = 12 \text{ A}$, $V_{GS} = 0 \text{ V}$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$I_S = 12 \text{ A}$, $V_{GS} = 0 \text{ V}$ $dI_F/dt = 100 \text{ A}/\mu\text{s}$ (Note 4)	--	430	--	ns
Q_{rr}	Reverse Recovery Charge		--	5.0	--	μC

NOTES:

- Repetitive Rating: Pulse width limited by maximum junction temperature
- $L=11\text{mH}$, $I_{AS}=12\text{A}$, $V_{DD}=50\text{V}$, $R_G=25 \Omega$, Starting $T_J=25^\circ\text{C}$
- $I_{SD} \leq 12\text{A}$, $dI/dt \leq 200\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ\text{C}$
- Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$
- Essentially Independent of Operating Temperature Typical Characteristics

Typical Characteristics

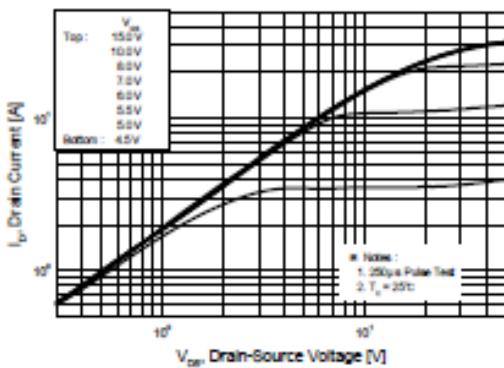


Figure 1. On-Region Characteristics

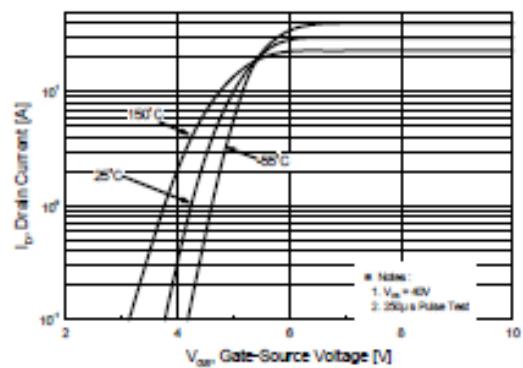


Figure 2. Transfer Characteristics

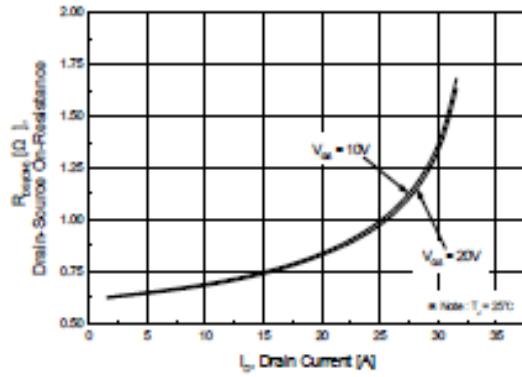


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

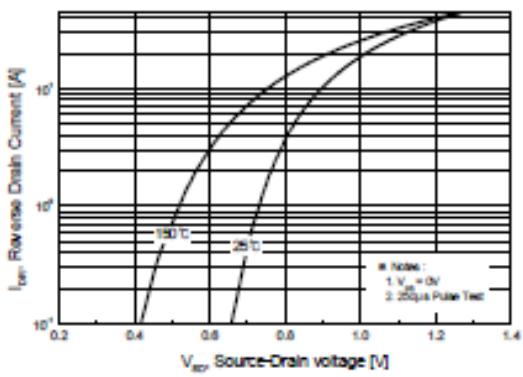


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

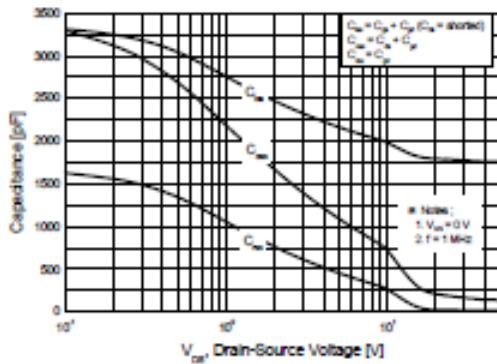


Figure 5. Capacitance Characteristics

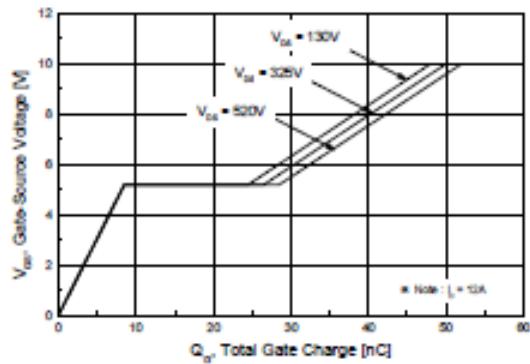


Figure 6. Gate Charge Characteristics

Typical Characteristics

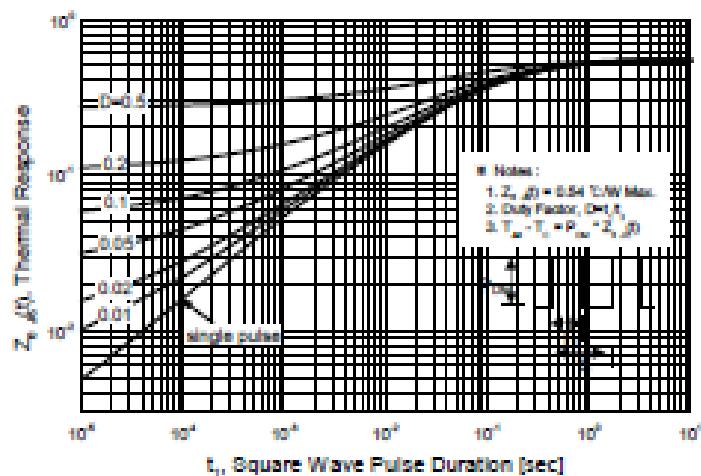
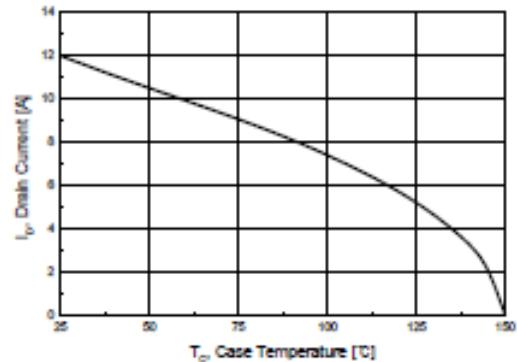
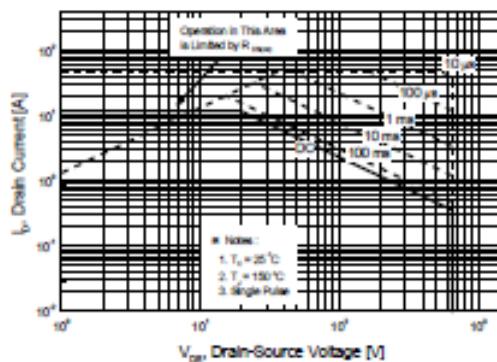
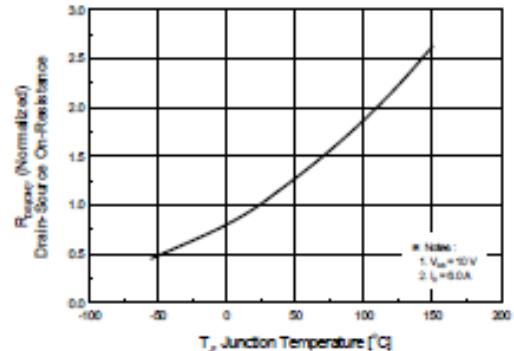
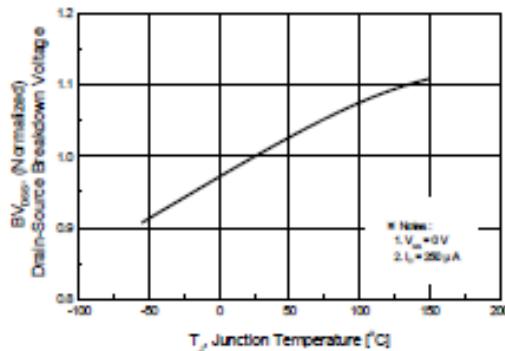


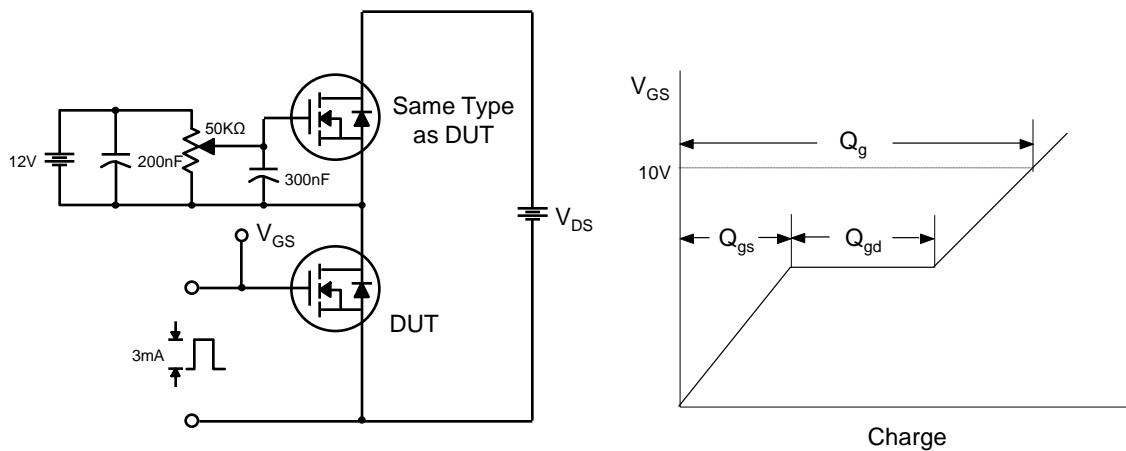
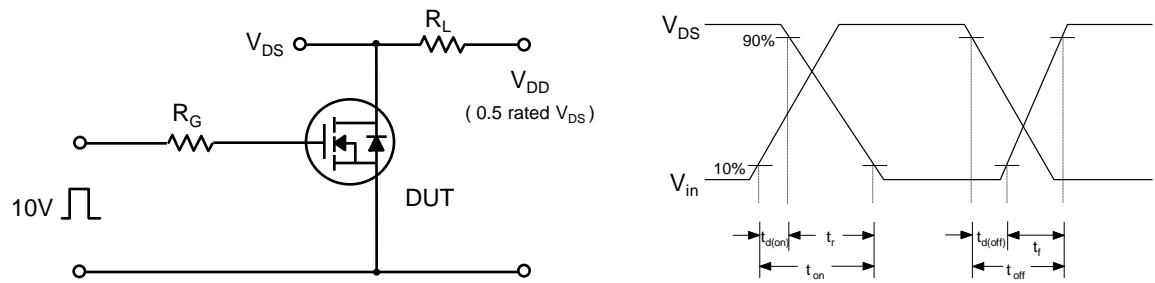
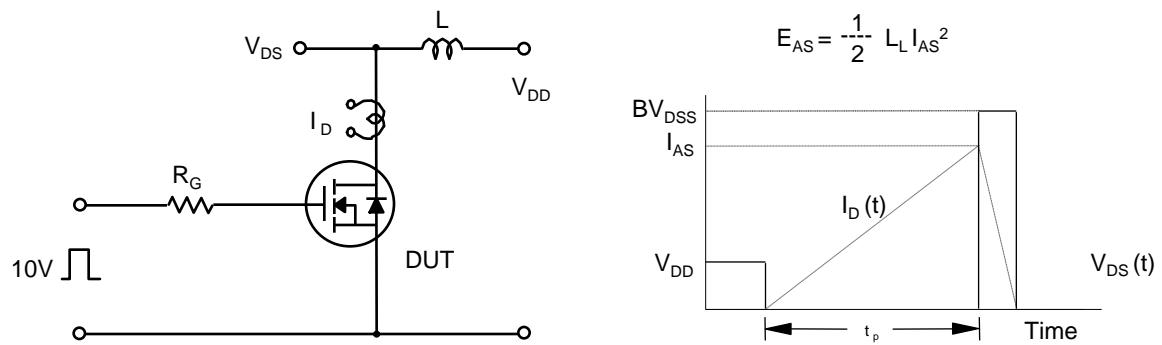
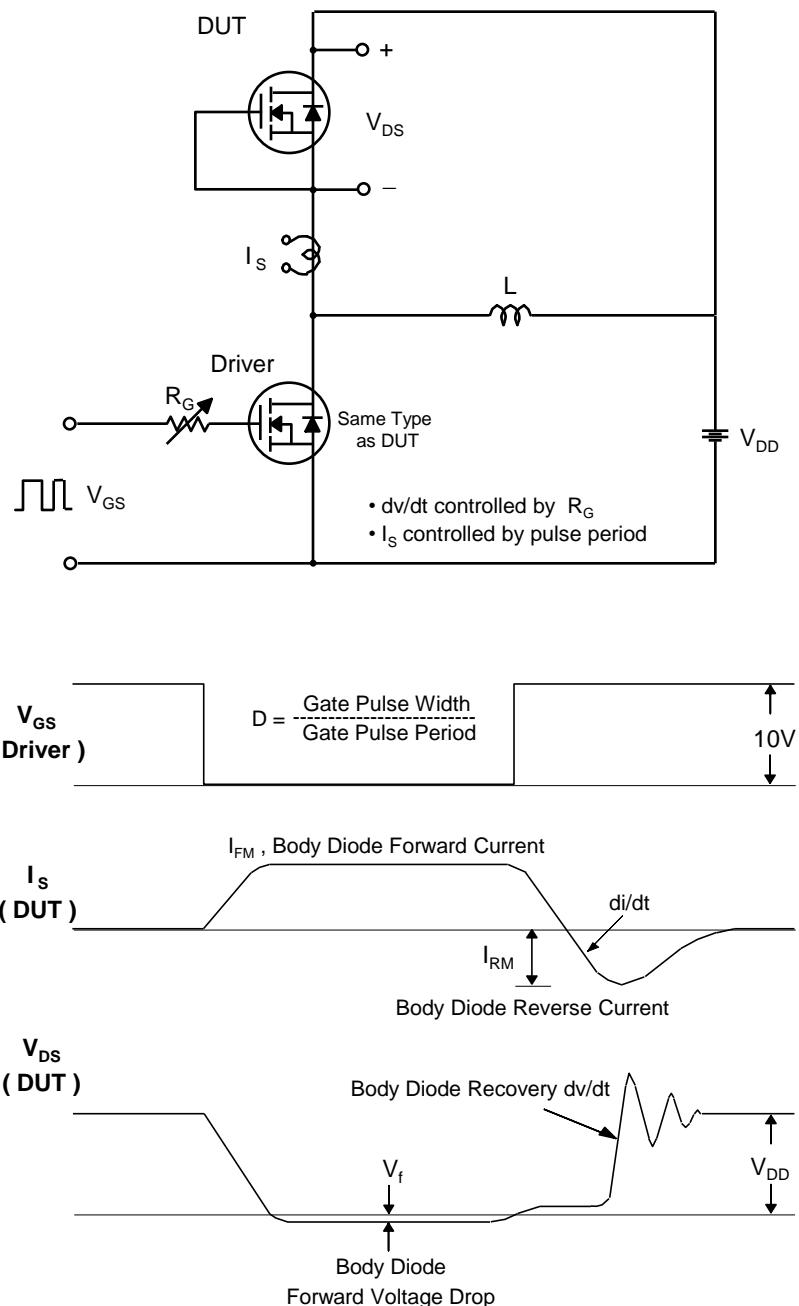
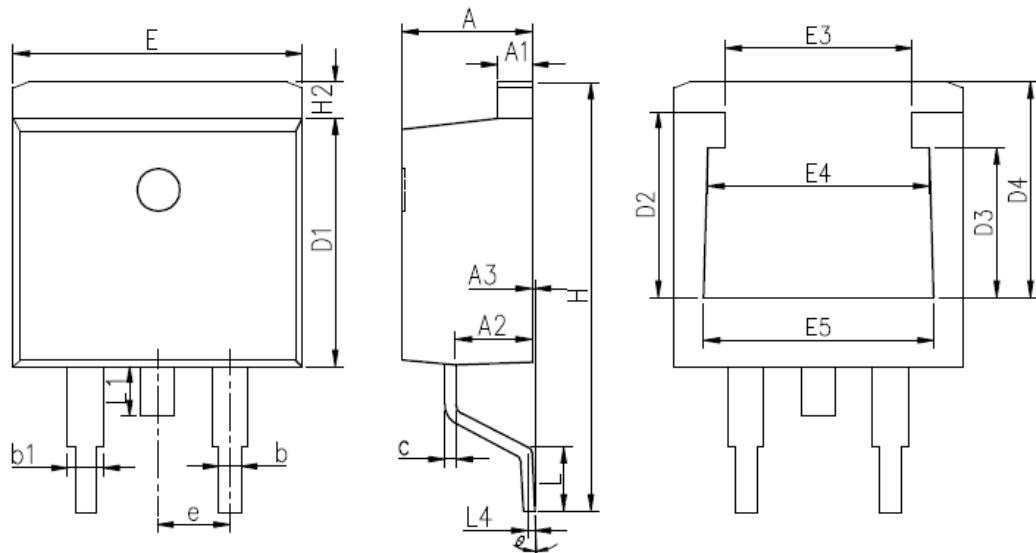
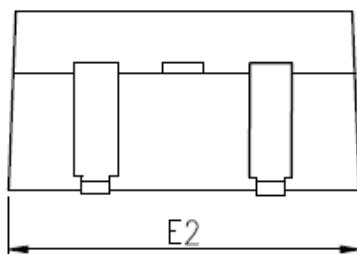
Fig 12. Gate Charge Test Circuit & Waveform**Fig 13. Resistive Switching Test Circuit & Waveforms****Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms**

Fig 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

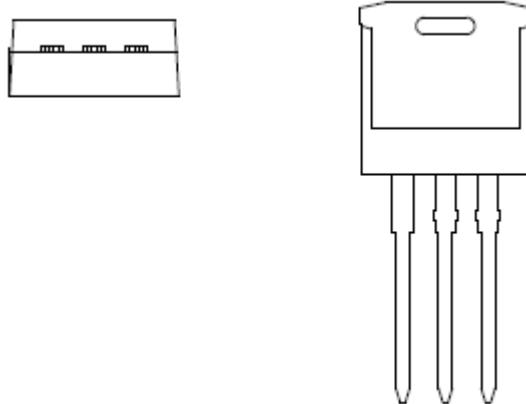
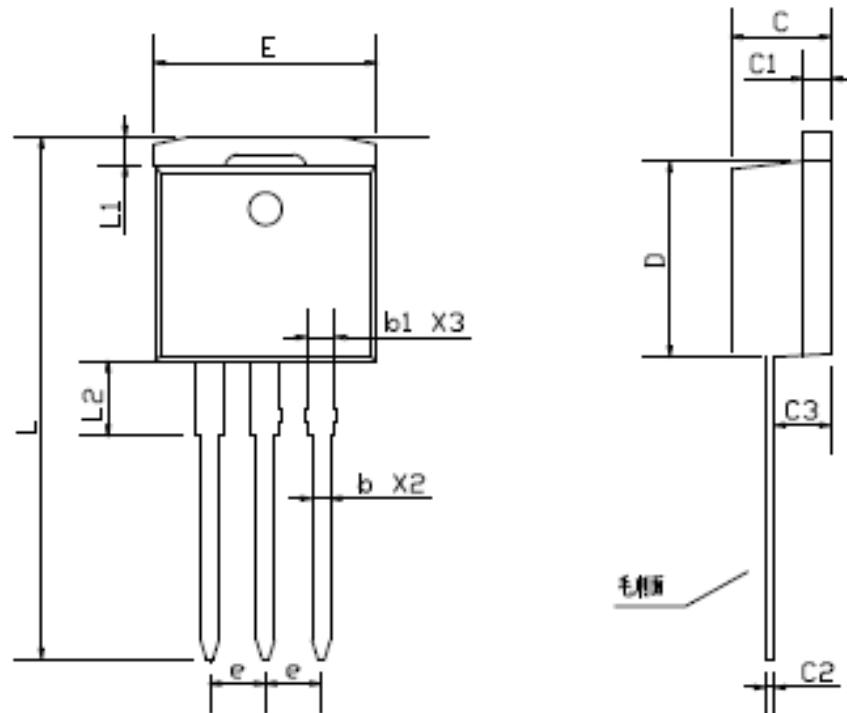


Package Dimension**TO-263****COMMON DIMENSIONS**

SYMBOL	MM		
	MIN	NOM	MAX
A	4.27	4.57	4.87
A1	1.22	1.27	1.42
A2	2.39	2.69	2.99
A3	0.00	0.13	0.20
b	0.70	0.81	1.01
b1	1.17	1.27	1.50
c	0.30	0.38	0.53
D1	8.40	8.70	9.00
D2	5.33	6.33	6.63
D3	4.54	5.54	5.84
D4	6.60	7.60	8.00
E	9.88	10.16	10.50
E2	9.80	10.10	10.40
E3	4.94	5.94	6.24
E4	6.67	7.67	7.97
E5	7.06	8.06	8.36
e		2.54	BSC
H	14.70	15.10	15.50
H2	1.00	1.27	1.50
L	2.00	2.30	2.60
L1	1.35	1.55	1.75
L4		0.25	BSC
θ	0°	5°	9°

Package Dimension

TO-262



标注	单位 (mm)	
	MIN	MAX
E	9.80	10.50
L	23.35	24.20
L1	1.00	1.55
L2	3.05	3.85
b	0.60	0.99
b1	1.00	1.50
C	4.30	4.80
C1	1.10	1.45
C2	0.25	0.52
C3	2.40	2.80
D	8.50	9.50
e	Typical	2.54